



Sheet 1 of 1

FORM PTO-1449  
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.  
ASA-481-10SERIAL NO.  
10/777,060LIST OF DOCUMENTS CITED BY APPLICANT  
(Use several sheets if necessary)APPLICANT  
N. HASEGAWA et al.FILING DATE  
February 13, 2004GROUP  
1756

## U.S. PATENT DOCUMENTS

* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)
	AA					
	AB					
	AC					
	AD					
	AE					
	AF					
	AG					
	AH					
	AI					
	AJ					
	AK					

## FOREIGN PATENT DOCUMENTS

	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
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	AM					<input type="checkbox"/>	<input type="checkbox"/>
	AN					<input type="checkbox"/>	<input type="checkbox"/>
	AO					<input type="checkbox"/>	<input type="checkbox"/>
	AP					<input type="checkbox"/>	<input type="checkbox"/>

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

AR	Watanabe, et al., "Transparent Phase Shifting Mask"; IEDM Technical Digest. International Electron Devices Meeting 1990, pp. 821-824.
AS	Terasawa, et al., "Imaging Characteristics of Multi-Phase-Shifting and Halftone Phase-Shifting Masks." Japanese Journal of Applied Physics, Vol. 30, No. 11B (1991), pp. 2991-2997.
AT	

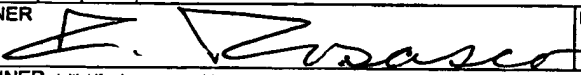
EXAMINER

DATE CONSIDERED

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 608; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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<b>LIST OF DOCUMENTS CITED BY APPLICANT</b> <i>(Use several sheets if necessary)</i>				APPLICANT N. HASEGAWA et al		GROUP 1756	
				FILING DATE 02/13/04			
<b>U.S. PATENT DOCUMENTS</b>							
* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE (If Appropriate)	
AR	AA	5,429,897	07/04/95	Yoshioka et al			
	AB	5,589,305	12/31/96	Tomofuji et al			
	AC	5,472,813	12/1995	Nakagawa et al			
	AD	5,574,492	11/1996	Suzuki			
	AE	4,360,586	11/23/82	Flanders et al			
	AF	4,890,309	12/26/89	Smith et al			
	AG	5,328,807	07/12/94	Tanaka et al			
	AH	5,364,716	11/15/94	Nakagawa et al			
	AI	5,837,405	11/17/98	Tomofuji et al			
	AJ	5,660,956	08/26/97	Tomofuji et al			
	AK	5,595,844	01/21/97	Tomofuji et al			
<b>FOREIGN PATENT DOCUMENTS</b>							
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						YES	NO
AR	AL	62-50811	10/27/87	Japan		<input type="checkbox"/>	<input type="checkbox"/>
	AM	4-136854	05/11/92	Japan		<input type="checkbox"/>	<input type="checkbox"/>
	AN	144453	06/19/91	Japan		<input type="checkbox"/>	<input type="checkbox"/>
	AO	269532	12/02/91	Japan		<input type="checkbox"/>	<input type="checkbox"/>
	AP	1750/95	02/28/95	Korea		<input type="checkbox"/>	<input type="checkbox"/>
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
AR	AS	Flanders et al, "Spatial period division - A new technique for exposing submicrometer-line width periodic and quasiperiodic patterns", JOURNAL OF VACUUM SCIENCE TECHNOLOGY, 16(6), Nov/Dec 1979, pp. 1949-1952					
	AT						
EXAMINER A. Dosasa				DATE CONSIDERED 8-5-05			

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	AA						
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AP						<input type="checkbox"/>	<input type="checkbox"/>
<b>OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
AR							
AS							
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